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APJ ABDUL KALAM TECHNOLOGICAL UNIVERSITY

Third Semester B.Tech Degree Examination December 2020 (2019 Schemer)

Course Code: ECT201 Course Name: SOLID STATE DEVICES

Duration: 3 Hours Max. Marks: 100 PART A Marks Answer all questions. Each question carries 3 marks With suitable examples, distinguish between elemental and compound (3)semiconductors. Give their applications. Draw the energy band diagrams under equilibrium for the following (3)semiconductors. i) intrinsic ii) n type iii) p type Write down the current equations in a semiconductor. (3) What is the significance of quasi fermi level? If there is gradient in quasi fermi (3)level, what does it indicates? Draw the V-I characteristics of a P N junction diode & mark the regions of (3)operation. Write down the ideal diode equation. (3) Draw the structure of a PNP transistor. Clearly Indicate the current components on the figure. Plot the transfer characteristics of an n-channel MOSFET. Give the current (3)equation. An nMOS transistor has W/L= 4/2, gate oxide thickness 40 A°, Mobility of (3)electrons 180 cm²/Vsec. The threshold voltage is 0.4 V, relative permittivity of gate oxide ϵ_{ox} =3.9. Calculate the drain current when Vgs = 1.5 V, Vds = 1.8 V. What is channel length modulation in MOSFETs? How does it affect the output (3)characteristics of the MOSFET? (3)Explain the principle of operation and advantage of FinFET. 10 PART B

Answer any one full question from each module. Each question carries 14 marks

Module 1

11 a) Derive the equation for hole concentration in a semiconductor under thermal (8) equilibrium in terms of n_i, E_f and E_i.

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- b) A silicon sample doped with $2x10^{16}$ cm⁻³ of Boron atoms. ($n_i = 1.5x10^{10}$ cm⁻³ for Silicon at 300 K) Determine,
 - i. The equilibrium electron and hole concentrations
 - ii. Position of fermi energy level in the band gap

(6)

(4)

(6)

- iii. Plot the energy band diagram
- 12 a) Plot and explain the temperature dependence of intrinsic carrier concentration (4) in semiconductors
 - b) With suitable sketches explain the indirect recombination mechanism via (5) traps.
 - c) An n-type Si sample with Nd = 10^{15} cm⁻³ is steadily illuminated such that g_{op} (5) = 10^{21} EHP/cm³s. If $\tau_n = \tau_p = 1 \ \mu s$ for this excitation, calculate the separation in the quasi-Fermi levels, (F_n - F_p). ($n_i = 1.5 \times 10^{10}$ cm⁻³ for Silicon at 300 K)

Module 2

- a) Explain the term mobility with respect to semiconductors. What are the (8) factors on which the mobility depends on? Explain the variation of mobility with temperature and doping.
 - b) A potential of 100 mV is applied across a semiconductor bar, and the resulting current is 1 mA. A magnetic field of 10⁻⁴ Wb/cm² is applied perpendicular to this semiconductor bar. The hall voltage measured is -2 (6) mV. The dimensions of the bar are width = 0.1 mm, length = 5 mm and thickness = 10 μm. Find
 - i. the type of the semiconductor bar
 - ii. the concentration and the mobility of majority carriers
- 14 a) Derive continuity equation for holes.
 - b) Solve the continuity equation, under steady state conditions assuming the semiconductor is long and no drift current is present. Plot the solution.
 - c) A p type semiconductor injected at one end with minority carrier electrons, under steady state conditions. Na = 10^{15} cm⁻³, $\tau_n = 0.1 \ \mu s$, $\mu_n = 700 \ cm^2/V$ Sec. Calculate the electron diffusion length. (4)

Module 3

a) With the help of energy band diagrams, explain the behaviour of the contact (10) between a metal and an n-type semiconductor. Clearly distinguish between Schottky and ohmic contacts.

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- b) What is base width modulation? How does it affect the input and output (4) characteristics of a BJT? a) Derive the equation for the built in potential of a PN junction under thermal 16 (7)equilibrium. b) A PN junction, doped on one side with 10¹⁸ cm⁻³ Boron atoms and the other side with 10^{16} cm⁻³ of Arsenic atoms at 300 K. (n_i = 1.5×10^{10} cm⁻³ at 300 K (3) and $\epsilon_r = 11.9$ for Silicon). Calculate, the built in potential. c) The following parameters are given for a PNP transistor. I_{EP} = 2 mA, I_{En} = 0.01 mA, I_{cP} = 1.98 mA and I_{cn} = 0.001mA. Determine i. The base transport factor ii. The emitter injection efficiency (4) iii. α and β Module 4 17 a) Draw and explain the C-V Characteristics of an Ideal MOS capacitor. Derive (8) the expression for threshold voltage.
 - b) Draw the energy band diagrams, of an ideal MOS capacitor under equilibrium, and strong inversion conditions.

(6)

(7)

- a) Draw the structure of n channel MOSFET. Derive the expression for drain (10) current of a MOSFET in the two regions of operation. What are the assumptions made in deriving the expression?
 - b) What is meant by body effect in MOSFET? How does it affect the threshold (4) voltage of the MOSFET?

Module 5

- 19 a) What is meant by scaling in MOSFETs? Explain the challenges in device (7) scaling?
 - b) Explain the concept of constant voltage scaling and its limitations.
- 20 a) What is meant by DIBL in MOSFETs? How does it affect the threshold (7) voltage of a MOSFET?
 - b) Explain the concepts of velocity saturation and hot carrier effects in a (7) MOSFET.
